

Microwave Measurements . . . The Quiet Revolution

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Abstract

We live at a time when major changes are occurring in the way we live our everyday lives. Many of these changes are being brought about by advancements in technology achieved via ground-breaking research in science and engineering. A requirement with any new technology is the need to validate performance through reliable test and measurement. New technologies often require new types of measurement to be developed in order to be fit-for-purpose. This talk describes some of the recent developments that have occurred in the area of microwave measurements in order to keep pace with the new developments taking place in science, engineering and technology. These measurements are impacting areas such as telecommunications, computing, security, healthcare and climate change monitoring. The talk shows how microwave measurements are being adapted and extended to cater for new technologies that underpin these areas. Several examples are given showing the current state-of-the-art for these types of measurement.

This lecture is based on the Keynote/Plenary Lecture that was given during the Closing Ceremony of European Microwave Week, which took place in London in October 2016.